

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO.  00-VE04.75ACIP	SERIAL NO.  09/767,902		
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT(S): Doskow et al.			
				FILING DATE 01/24/2001		GROUP 2614	
<b>U.S. PATENT DOCUMENTS</b>							
* EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
QN		5,881,132	03/1999	O'Brien et al.			
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QN		2004/0042609	03/04/04	Delaney et al.			
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES      NO
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
QN		Schneier, "Applied Crpytography", 1996, John Wiley, 2 <sup>nd</sup> Edition, pages 38, 576-577					
EXAMINER  /Quynh Nguyen/				DATE CONSIDERED      10/11/2006			
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							